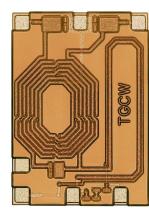
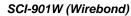


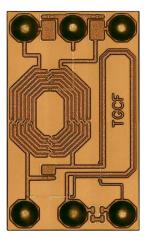
# (36) GSM Band Balun with Coupler (SCI-901 W/F)

#### **FEATURES**

- Passive integration on silicon substrate
- · Low insertion loss in pass band
- Small size: 1.6 mm x 1.2 mm (wirebond)
  2.0 mm x 1.2 mm (flip chip)
- Pb-free solder bump
- Low profile: 0.25 mm height (wirebond)
  0.40 mm height (flip chip)
- Directly attachable on PCB or flipped on PCB
- Operating temperature: -40  $^{\circ}$ C to +85  $^{\circ}$ C
- Storage temperature: -40  $^{\circ}$ C to +85  $^{\circ}$ C







SCI-901F (Flip Chip)

#### **DESCRIPTION**

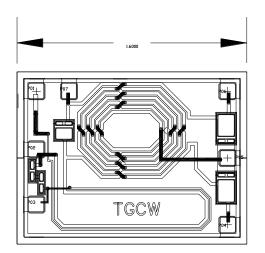
STATS ChipPAC's SCI-901W/F is a balun with coupler for GSM band applications. The IPD has low passband insertion loss and small size. It is composed of thick copper inductors and Metal-Insulator-Metal capacitors which are fabricated on a silicon substrate using our IPD (Integrated Passive Device) process. The pad or bump size and pitch of the IPD are selected so that the device can be mounted directly on a PCB or laminate substrate using conventional wirebonding or surface mount techniques. The low profile and small form-factor of the device make it especially suitable for SiP applications.

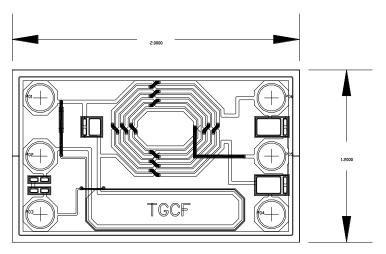
#### **ELECTRICAL SPECIFICATIONS**

#### (Test board loss 0.04 dB included)

Specification	Unit	Min.	Typical	Max.
Pass Band	MHz	824		915
Insertion Loss	dB			1.1
Return Loss	dB	15		
Differential Impedance	Ohm		100	
Amplitude Imbalance	dB			0.3
Phase Imbalance	deg			6.0
Coupling Coefficient	dB		-20	
Directivity	dB		20	
Size	mm	1.6 x 1.2 (WB)		2.0 x 1.2 (FC)

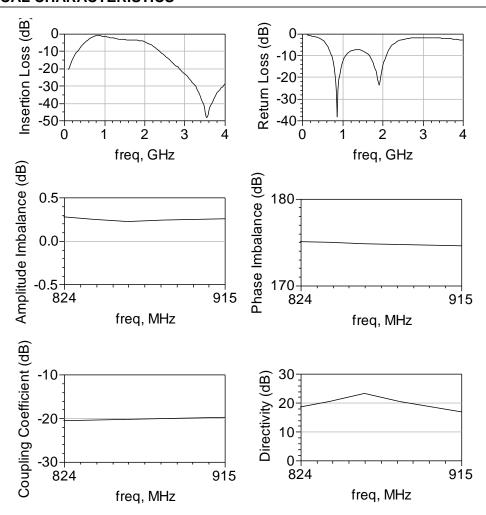
#### **DIMENSIONS**





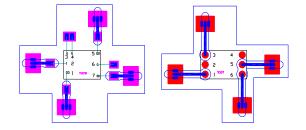


## TYPICAL CHARACTERISTICS



#### **TEST BOARD DRAWING**

# SCI-901W (Wirebond) SCI-901F (Flip Chip)



Pad	SCI-901W Signal	SCI-901F Signal
1	Coupling	Balanced (+)
2	Unbalanced	GND
3	GND	Balanced (-)
4	GND	GND
5	Balanced (+)	Unbalanced
6	GND	Coupling
7	Balanced (-)	

### **NOTES**

All dimension measurement units are in millimeters (mm). Electrical performance and typical values are measured at room temperature. For best results, ground plane directly beneath the device should be in the top metal layer.

Refer to "Appendix A" for:

- Pad sizes and typical wirebond length used in the wirebonded IPD products.
- Recommended solder thermal profile, landing pattern recommendation and bump specifications used in the flip chip IPD products.